

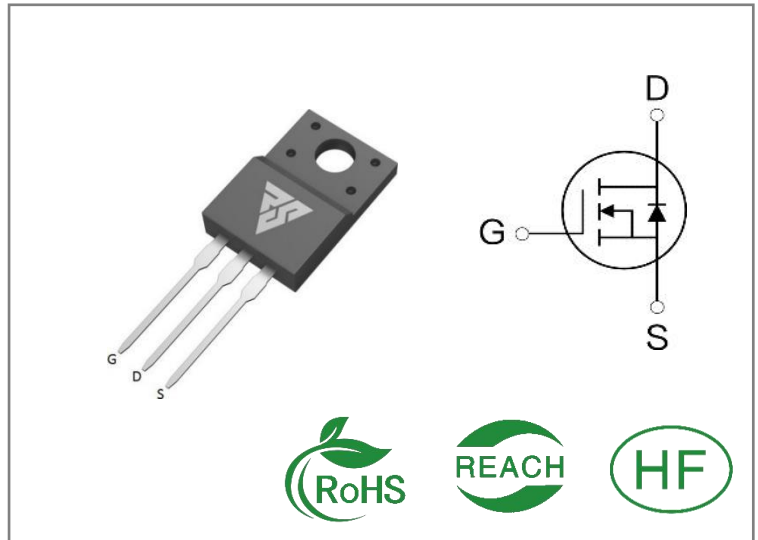
ID	$R_{DS(ON)}$ (Typ)	VDSS
15A	0.35Ω	500V

#### Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

#### Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



#### Ordering Information

Part Number	Package	Marking	Packing	Qty.
RS15N50F	T0-220F	RS15N50F	Tube	50 PCS

#### Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	RS15N50F	Units
VDSS	Drain-to-Source Voltage	500	V
ID	Continuous Drain Current $T_C=25^\circ\text{C}$	15	A
	Continuous Drain Current $T_C=100^\circ\text{C}$	8.6	
IDM	Pulsed Drain Current (Note*1)	60	
PD	Power Dissipation	70	W
VGS	Gate- to- Source Voltage	$\pm 30$	V
EAS	Single Pulse Avalanche Energy $L = 10\text{mH}$ , $V_{DD} = 50\text{V}$ , $R_G = 25\ \Omega$	980	mJ
TL TPKG	Maximum Temperature for Soldering	300	$^\circ\text{C}$
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	260	
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

\* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.

### Thermal Resistance

Symbol	Parameter	RS15N50F	Units	Test Conditions
R $\theta$ JC	Junction-to-Case	1.78	°C / W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 °C
R $\theta$ JA	Junction-to- Ambient	60		1 cubic foot chamber,free air.

### OFF Characteristics TJ= 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	500	--	--	V	VGS=0V,ID=250μA
IDSS	Drain- to- Source Leakage Current	--	--	1	μA	VDS=500V,VGS=0 V
IGSS	Gate- to- Source Forward Leakage	--	--	100	nA	VGS=30V ,VDS=0V
	Gate- to- Source Reverse Leakage	--	--	-100		VGS=-30V ,VDS=0 V

### ON Characteristics TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-Resistance(Note*2)	--	0.35	0.42	Ω	VGS=10V,ID=7.5A
VGS(TH)	Gate Threshold Voltage	2	--	4	V	VGS=VDS,ID=250μA

### Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	34	--	nS	VDS=250V ID=15A RG=25Ω
trise	Rise Time	--	11	--		
td(OFF)	Turn- OFF Delay Time	--	95	--		
tfall	Fall Time	--	28	--		

**Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	1755	--	pF	VGS=0V VDS=25V f=1.0MHz
Coss	Output Capacitance	--	183	--		
Crss	Reverse Transfer Capacitance	--	11	--		
Qg	Total Gate Charge	--	44.3	--	nC	VDS=400V ID=15A VGS=10V
Qgs	Gate- to- Source Charge	--	8.5	--		
Qgd	Gate-to-Drain(" Miller") Charge	--	19.6	--		

**Source- Drain Diode Characteristics**

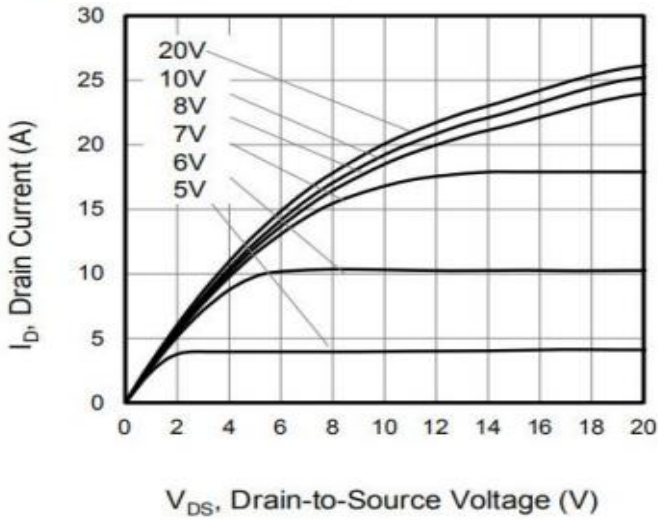
Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	15	A	Integral pn- diode in MOSFET
ISM	Maximum Pulsed Current	--	--	60	A	
VSD	Diode Forward Voltage	--	--	1.4	V	IS=7.5A,VGS=0V
trr	Reverse Recovery Time	--	389	--	nS	VGS=0V IS=15A,di/dt=100A /μs
Qrr	Reverse Recovery Charge	--	4.8	--	μC	

**Notes:**

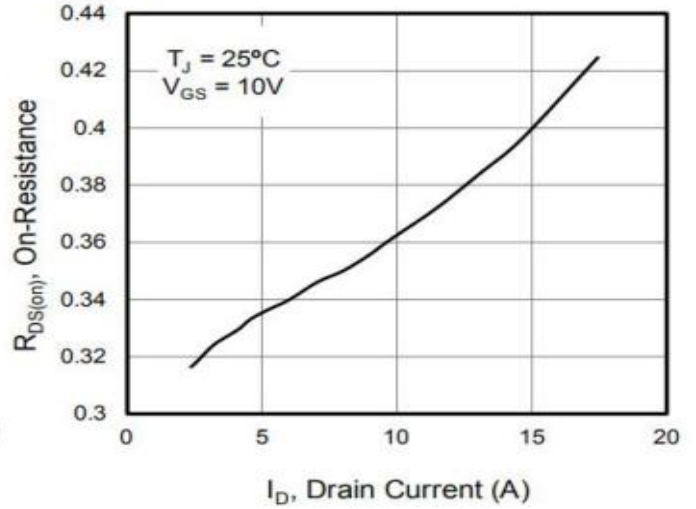
- \* 1. Repetitive rating,pulse width limited by maximum junction temperature.
- \* 2. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 1\%$

## Typical Feature Curve

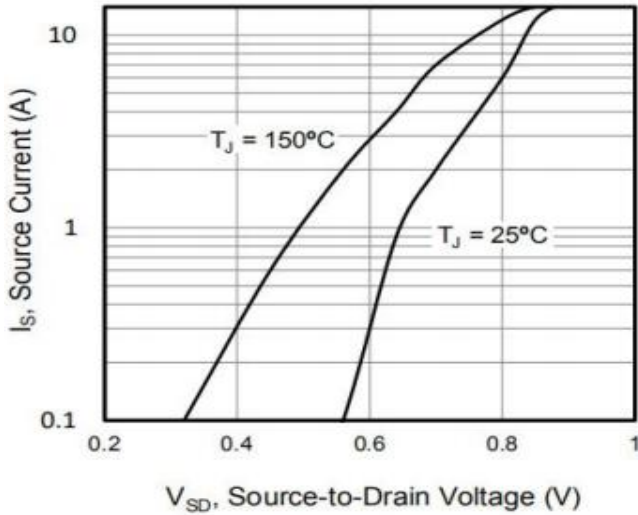
**Figure 1. Output Characteristics ( $T_J = 25^\circ\text{C}$ )**



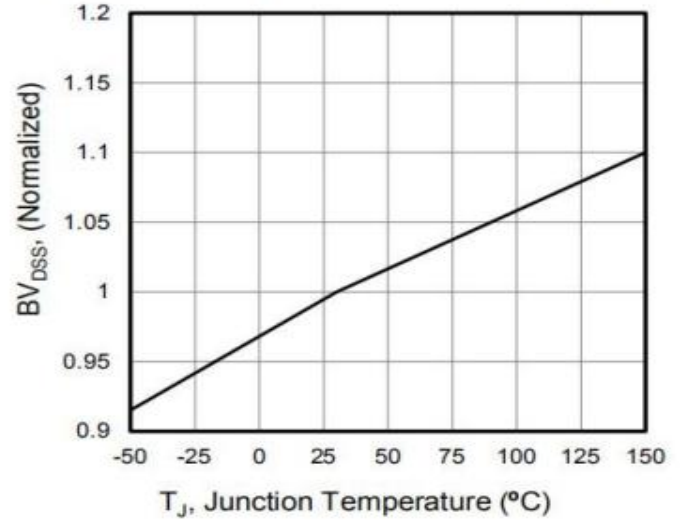
**Figure 2. On-Resistance vs. Drain**



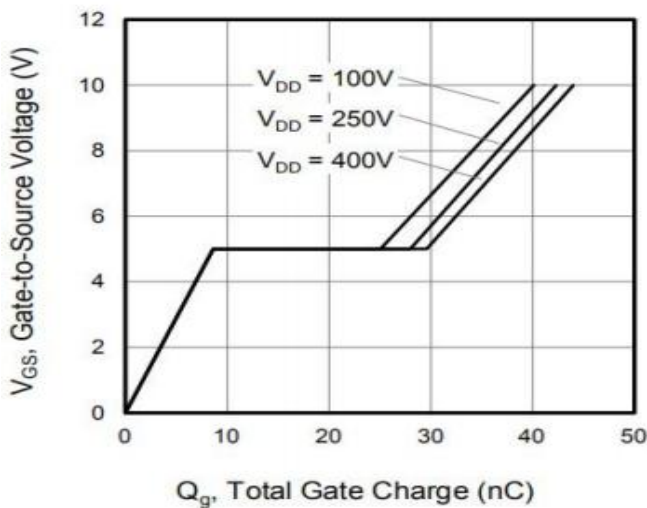
**Figure 3. Body Diode Forward Voltage**



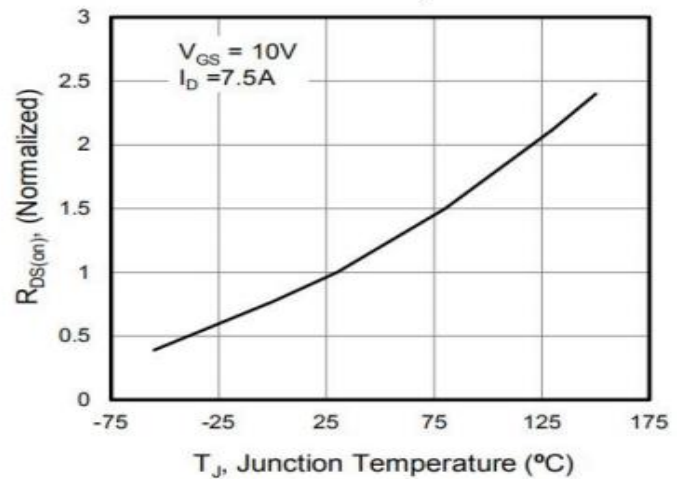
**Figure 4. BVDSS Variation vs. Temperature**



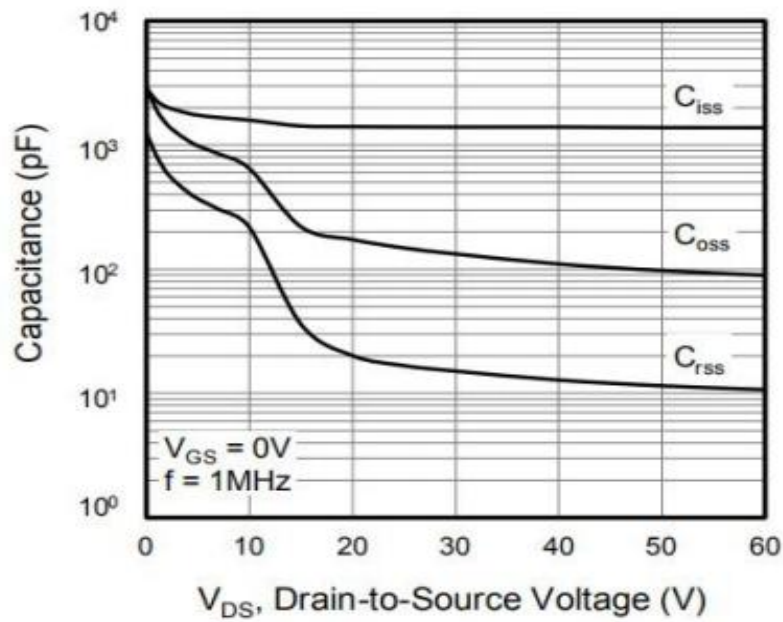
**Figure 5. Gate Charge**



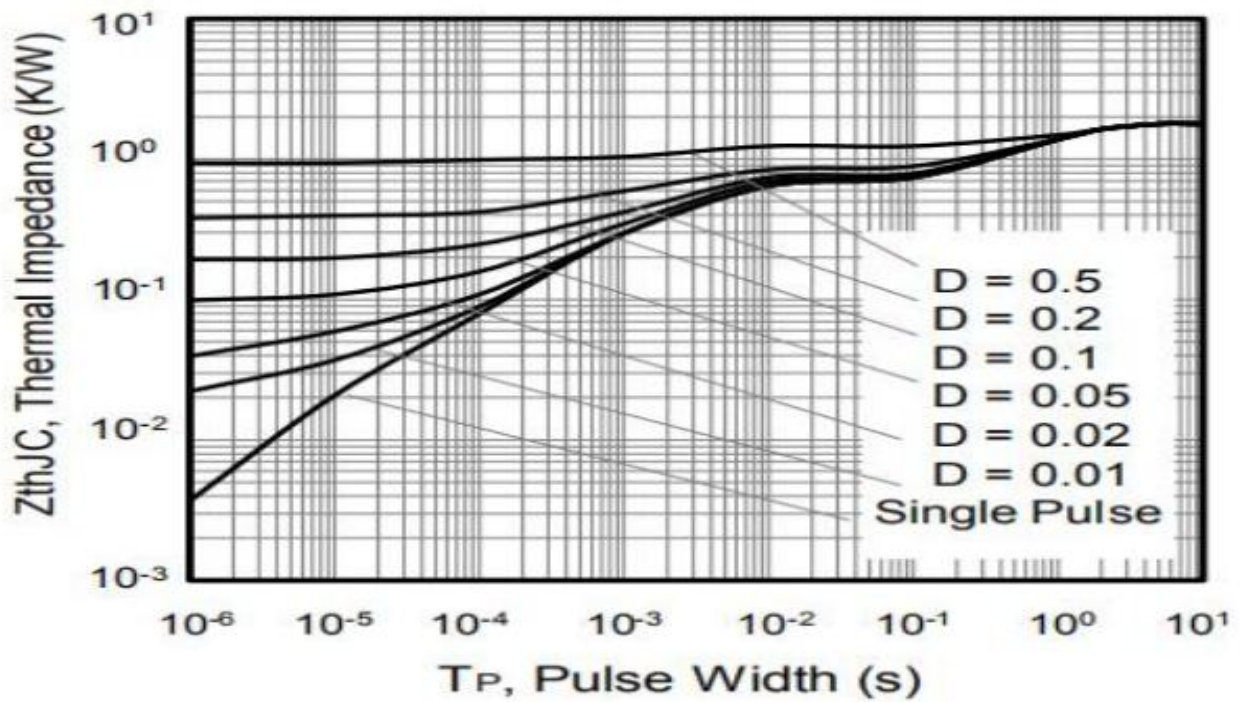
**Figure 6. On-Resistance vs. Temperature**



**Figure 7. Capacitance**

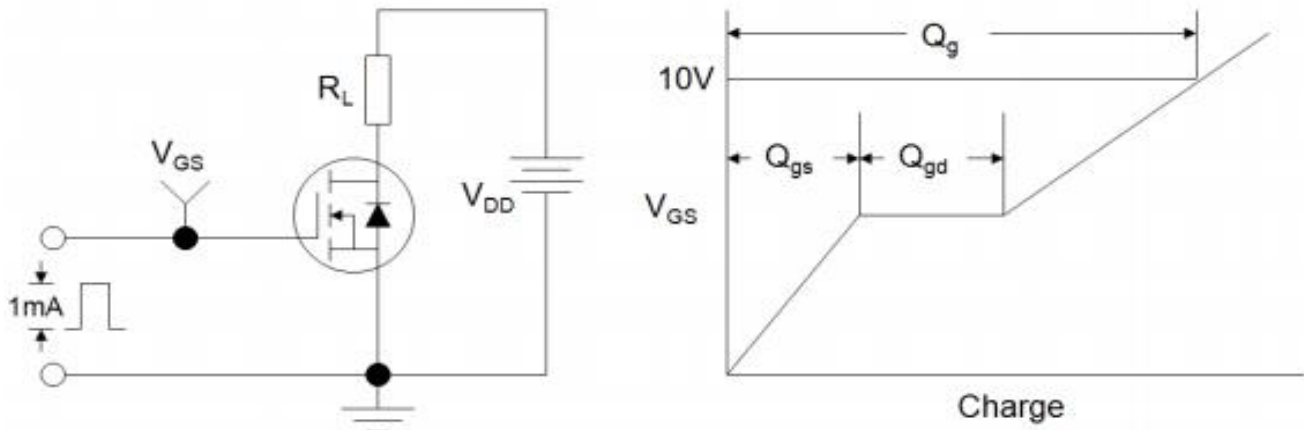


**Figure 8. Transient Thermal Impedance  
TO-220F**

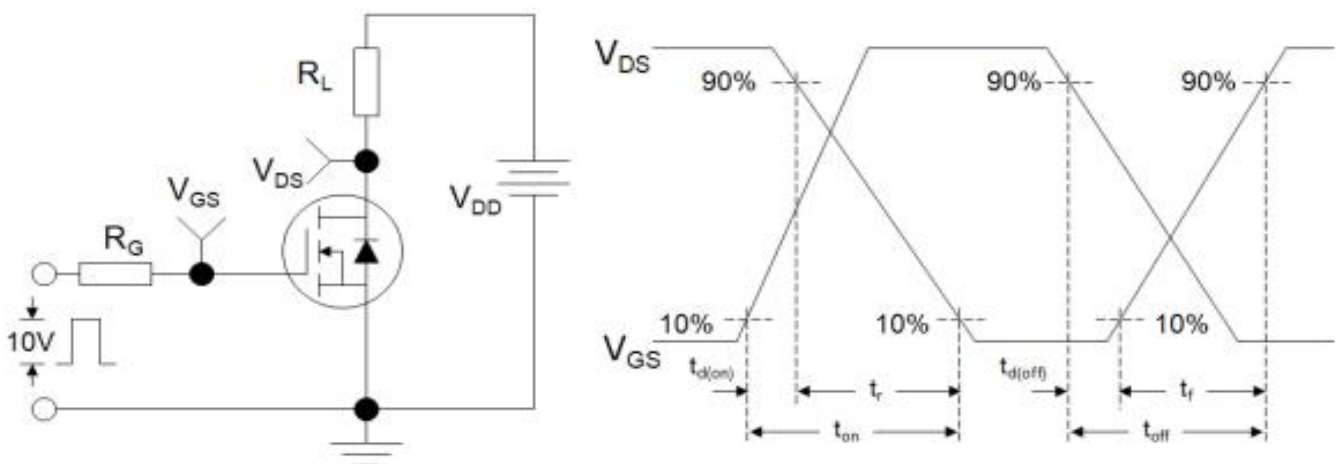


## Test Circuits and Waveforms

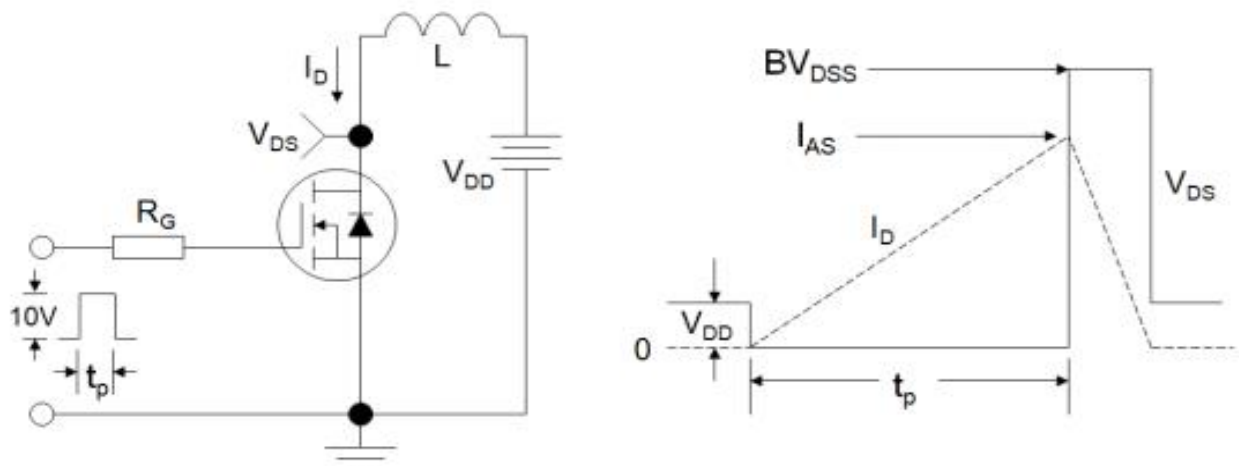
**Figure A: Gate Charge Test Circuit and Waveform**



**Figure B: Resistive Switching Test Circuit and Waveform**

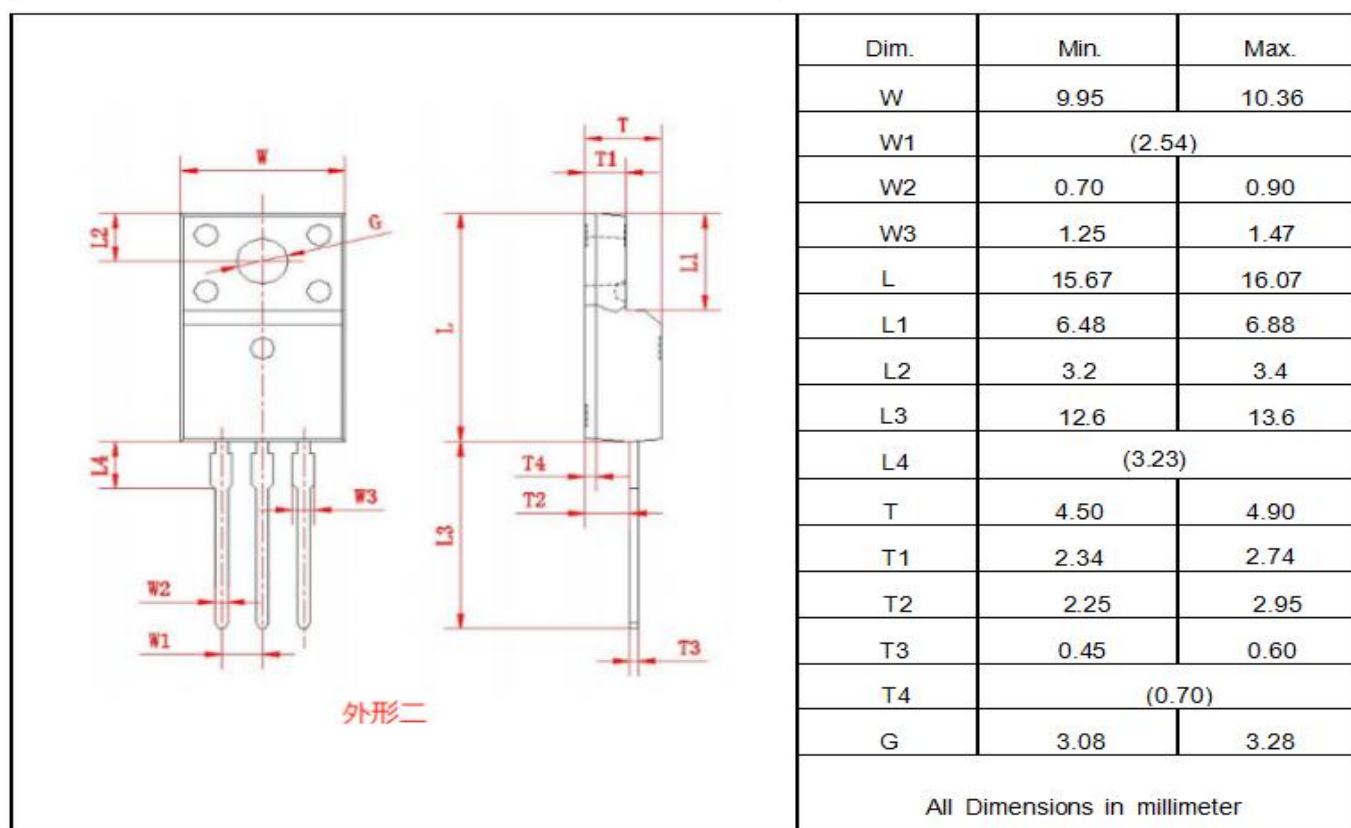
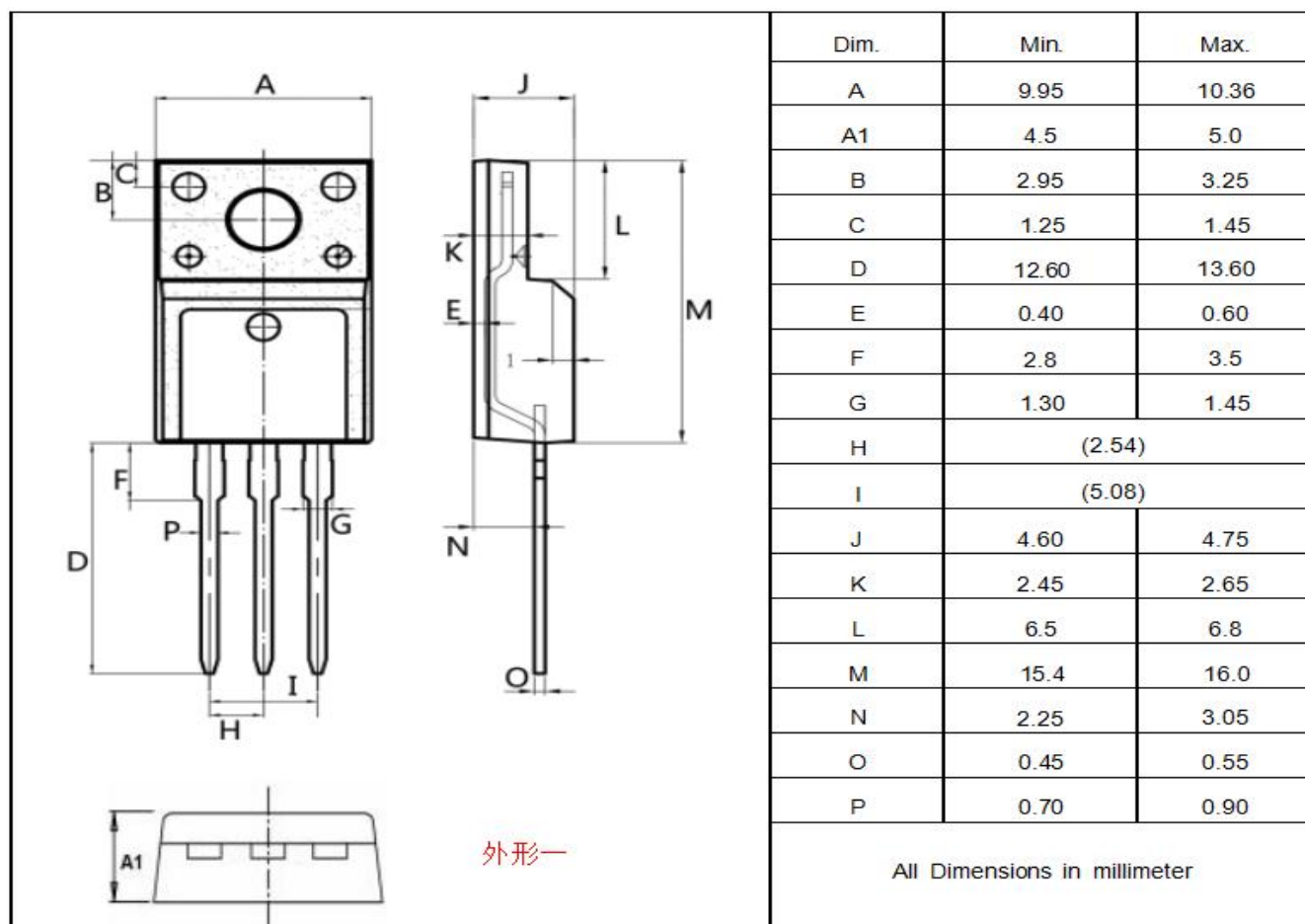


**Figure C: Unclamped Inductive Switching Test Circuit and Waveform**





Package outline drawing(TO-220F Unit: mm )



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